



Solid-State Power Generation and Cooling Micro/Nanodevices for Distributed System Architectures

Presented at the

20th International Conference on Thermoelectrics
Beijing, P.R. China

June 8-11, 2001

by

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Acknowledgments



- Jet Propulsion Laboratory
 - Power Materials & Device Technologies Group
 - G. J. Snyder, C.-K. Huang, M.A. Ryan, J. A. Herman, A. Borshchevsky, R. Williams and T. Caillat
 - Thermal Design Group
 - P. Shakkottai
 - Center for Integrated Space Microelectronics
 - E. Kolawa
- Partners and collaborators
 - UCLA
 - G. Chen
 - MIT, UC Berkeley, Howard University, UC Santa Barbara
 - M. Dresselhaus, A. Stacy, T. Huber, G. Stucky
 - USC/MemGen Inc.
 - P. Ronney, A. Cohen
 - Boston U. and U. Houston
 - B. Goldberg, S. Unlü, S. Pei
 - US CECOM
 - E. Plichta, M. Hendrickson
- Work is currently supported by:
 - Defense Advanced Research Projects Agency (DARPA)
 - Office of Naval Research (ONR)
 - NASA/JPL (CISM/SOAC and SP/Advanced Concepts)

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Advanced Thermoelectric Devices



- Even with a small improvement in ZT, TE applications could be extended to new fields

- Sometimes, cost or specific power and not efficiency is the important parameter!

- Power generation

- Waste heat recovery
 - ♦ Bottoming or topping cycles
 - microdevices
 - ♦ for cryobots, hydrobots...microbots
 - ♦ low power electronic devices

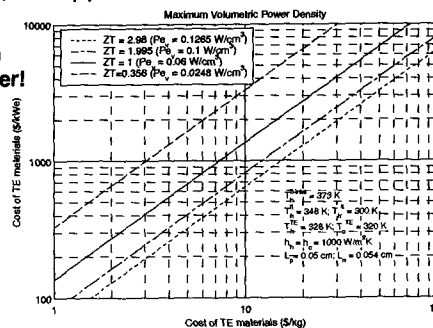


- Cooling

- Cryocoolers at $T < 100\text{K}$
 - microcoolers
 - ♦ For integration in thermal management packages

- Sensors

- Using temperature variations linked to radiation, electrical energy...
 - ♦ Integration with CMOS technology, MEMS techniques

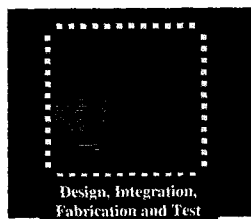


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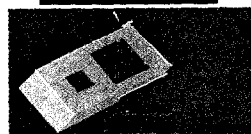
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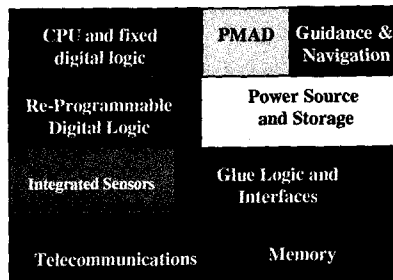
System On A Chip Technology



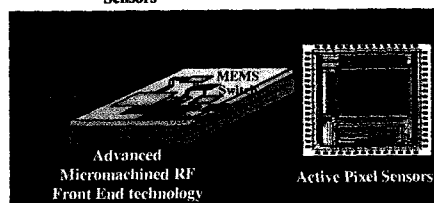
Design, Integration, Fabrication and Test



Sensors



On-Chip Power Source



Advanced Micromachined RF Front End technology

Active Pixel Sensors



PMAD

Thin film microtransformers

Embedded passive components

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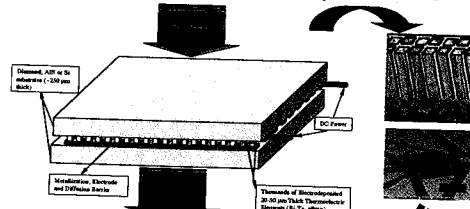
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TE Micro/Nanodevices at JPL



- **Objective:** Develop thermoelectric micro/nanodevices using integrated-circuit type fabrication processes, electrochemical deposition/CVD and high thermal conductivity substrates

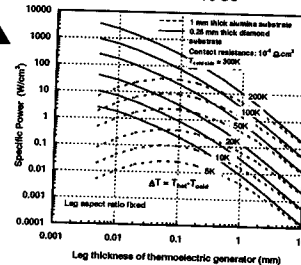


■ Technical Approach

- ◆ Synthesize 1-100 μm thick thermoelectric elements using electrochemical deposition/CVD
 - Study new materials and low dimensional structures (nanowires)
- ◆ Develop stable metallization to diamond, AlN, Si substrates
- ◆ Develop novel techniques to fabricate microdevices

■ Benefits and applications

- ◆ High specific power (W/cm^2) for cooling, and electrical power generation
 - Ability to generate high voltages even under low ΔT , heat flux conditions
- ◆ High degree of integration between thermal management/power and electronics
 - System-on-a-chip concept
 - Co-location of sense, actuate, command, power, communicate and thermal management functions
 - Use for power electronics, distributed sensor networks



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Thermal Management

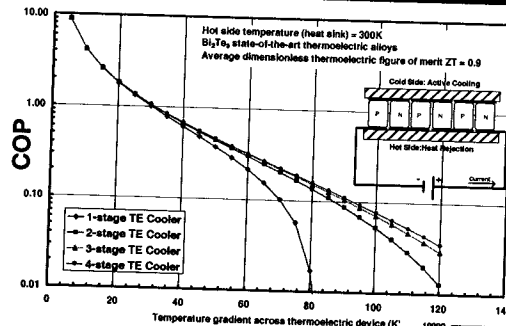
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Thermoelectric Cooling



- ◆ COP inversely proportional to ΔT and increases with increasing ZT
- ◆ Devices can be designed to function at maximum power or maximum efficiency

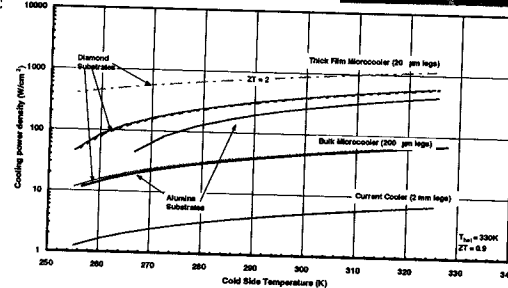
◆ TE Device is scalable



$$COP = \frac{Q_{cold}}{P_{el}} = \frac{S_{pn} T_{cold} I - \frac{1}{2} R I^2 - K(T_{hot} - T_{cold})}{S_{pn}(T_{hot} - T_{cold}) I + R I^2}$$

$$Q_{cold}^{max} = \frac{A}{l} \left[\frac{1}{2} \frac{S_{pn}^2 T_{cold}^2}{\rho_{pn}} - \lambda_{pn}(T_{hot} - T_{cold}) \right]$$

$$ZT = \frac{S^2 T}{\rho \lambda}$$



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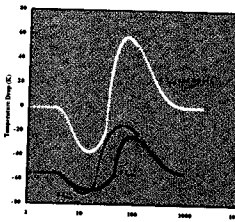
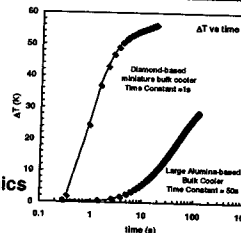
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Thermoelectric Microdevices



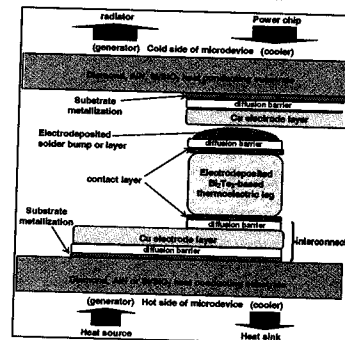
Miniaturized TE devices

- High power densities
 - ◆ Both cooling, electrical
 - ◆ High voltage operation
- High degree of integration
 - ◆ With electronics, optoelectronics
- Fast response time
 - ◆ "ms" instead of "s" to reach ΔT_{max}
 - ◆ Pulse operation can be considered



Miniaturized configuration at JPL

- Vertically integrated module
 - ◆ Higher heat losses for planar devices
- Key differences with bulk devices
 - ◆ Thousands of p-n junctions
 - ◆ High thermal conductivity substrates
 - ◆ Thermally stable metallizations
 - ◆ Electrochemical deposition
 - Thick films of semiconductors, metals
 - ◆ Integrated circuit processing techniques



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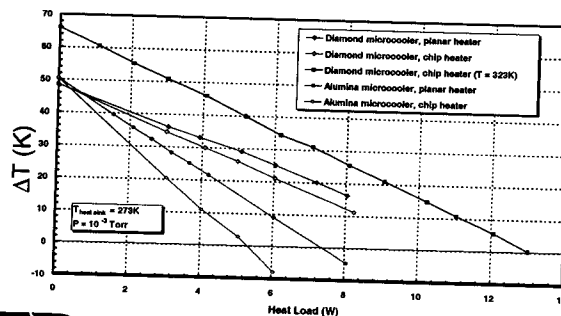
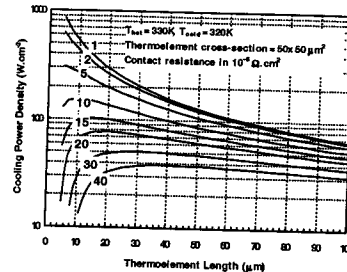


Thermoelectric Microdevices Issues



■ Miniaturization issues to be considered

- **Electrical contact resistance**
 - ♦ The shorter the leg, the more critical the electrical contact resistance
 - ♦ Develop high quality metallization and bonding schemes
- **Mechanical integrity**
 - ♦ Thermal stress due to large temperature differentials, non-uniform heat spreading



• Thermal resistance

- ♦ Due to substrates, packaging
 - Importance increases as leg thickness decreases
- ♦ High heat fluxes
 - Heat spreading
- ♦ Heat transfer is key
- ♦ Use high thermal conductivity substrates such as:
 - Diamond, AlN, Si/SiO₂

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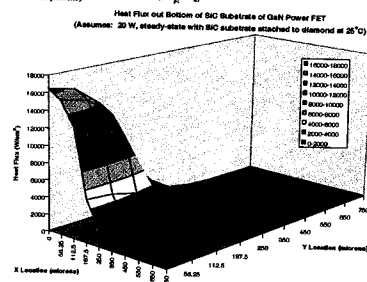
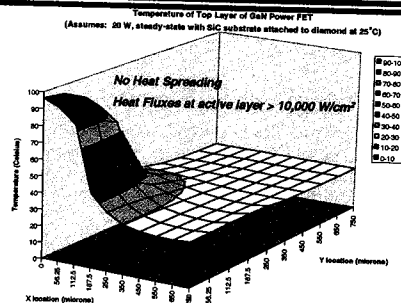
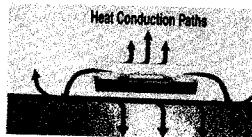
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Thermal Management of High Power Electronics



- **20W GaN device/die/diamond-based cooler/heat sink**
 - Next generation solid state power amplifier
- **Results indicate chip operating temperature too high**
 - Mostly due to temperature gradient across chip substrate
 - Active area (200x200 μm²) much smaller than SiC die (2x3 mm²)



■ Requires active cooling

- Cool below ambient back of the power chip
 - ♦ So that active electronic layer to remain below 100°C
 - ♦ Single-stage/multi-stage thermoelectric device to offset chip ΔT
- Critical that cooler be as close to power producing portion of device
 - ♦ Attach cooler to die using high thermal conductivity materials
 - ♦ If device much smaller than cooler then use diamond heat spreader
- Additional heat sinking technique required
 - ♦ To conduct heat away from cooler hot side
 - ♦ Where it can be safely dissipated

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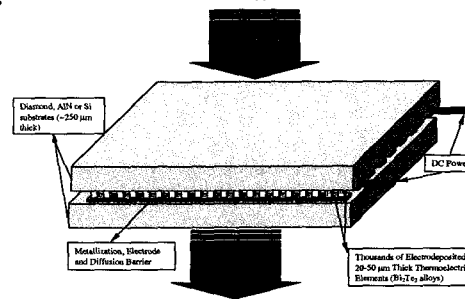
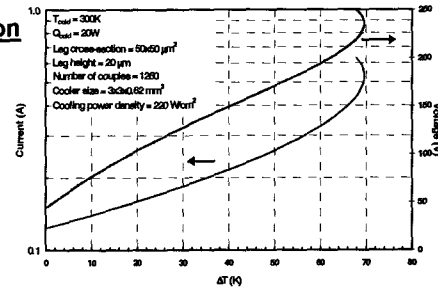


High Power TE Microcooler



TE microcoolers: a potential configuration

- Cooling of power chip dissipating $20W_{th}$
 - Power amplifier
 - ♦ Active junctions size: $200 \times 300 \mu m^2$
 - ♦ SiC die size: $2 \times 3 mm^2$
 - Thermoelectric microcooler
 - ♦ Cooler dimensions: $3 \times 3 mm^2$ cross section, $0.63 mm$ thick
 - ♦ 1250 thermocouples
 - ♦ leg size: $50 \times 50 \mu m^2$ cross-section, $20 \mu m$ thickness
 - Cooling performance at $30K \Delta T$:
 - ♦ Power input: $21.1 W$
 - ♦ Heat rejected: $41.2 W$
 - ♦ Current: $0.32 A$ and voltage: $66 V$
 - Cooling performance at $50K \Delta T$:
 - ♦ Power input: $50.2 W$
 - ♦ Heat rejected: $70.2 W$
 - ♦ Current: $0.48 A$ and voltage: $104 V$
 - Lower voltage, higher current, higher ΔT possible
 - ♦ Internal parallel connections, multistage configurations



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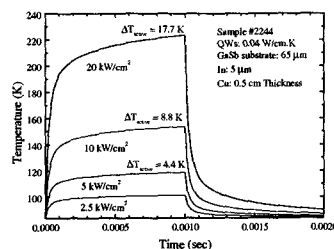
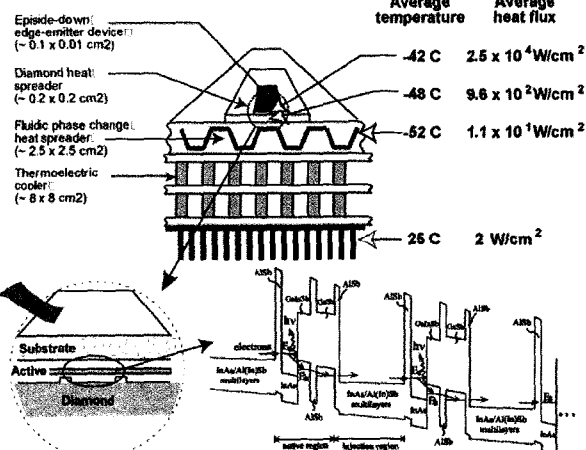


Cooling for Low-Power Optoelectronics



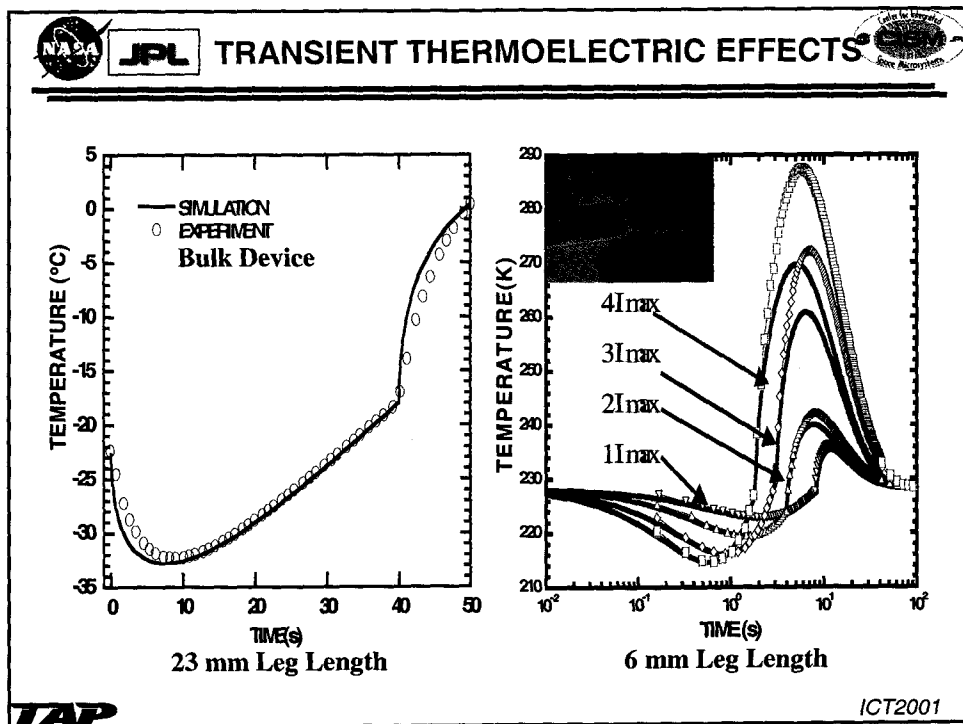
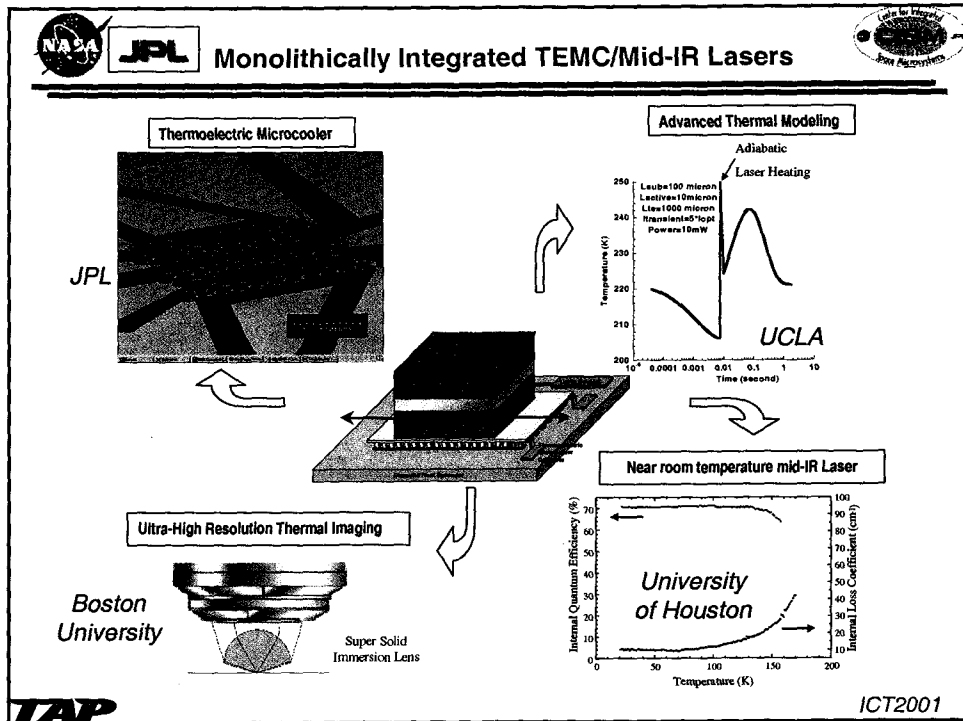
Mid-IR Lasers

- Major Heating Problem!!!
 - > 1000 layers and hetero-interfaces
 - Superlattice structure has much poorer thermal conductivity
 - Active region could be much hotter (> 100 °C) than the heat sink



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Power Generation

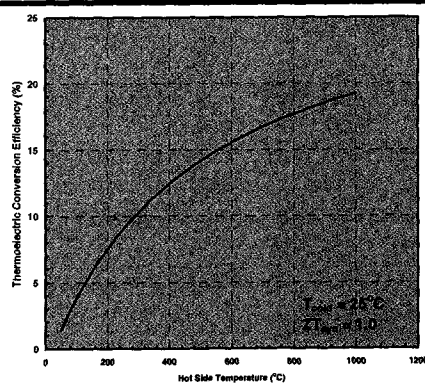
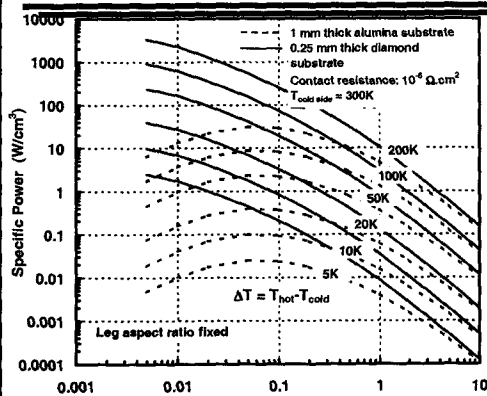
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Thermoelectric Power generation



Leg thickness of thermoelectric generator (mm)

$$\eta = \frac{P_{el}}{Q_{hot}} = \frac{R_{Load} I^2}{S_{pn} T_{hot} I - \frac{1}{2} R I^2 + K(T_{hot} - T_{cold})}$$

$$P_{el}^{max} = \frac{A}{l} \left[\frac{1}{4} \frac{S_{pn}^2 (T_{hot} - T_{cold})^2}{\rho_{pn}} \right]$$

$$ZT = \frac{S^2 T}{\rho \lambda}$$

- ◆ Energy conversion limited by Carnot efficiency and increases with increasing ΔT , ZT
- ◆ Devices can be designed to function at maximum power or maximum efficiency
- ◆ Thermoelectric device is scalable



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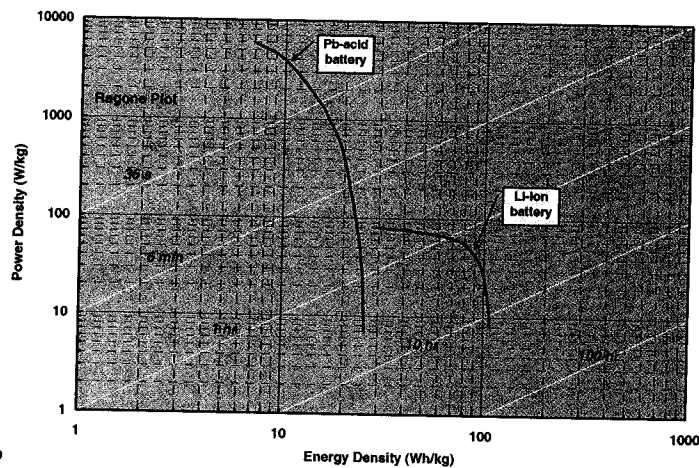


Need for Advanced Mobile Power Sources



High specific power and/or high specific energy requirements

- Thermoelectrics could contribute to solutions; for example:
 - High efficiency TE systems using high temperature source and/or hybrid conversion system
 - High specific power microdevice or high specific energy energy harvesting device



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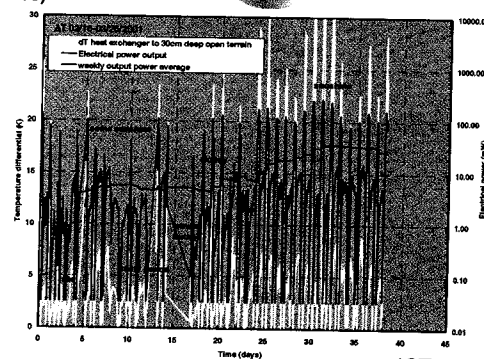
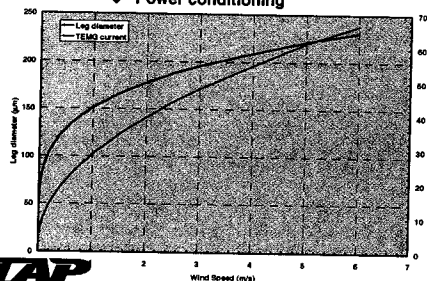
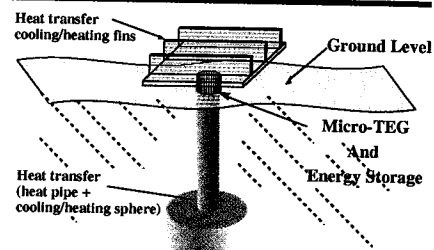


Energy Harvesting Concept



Environmental heat source development

- Use of natural temperature gradients
 - To provide 10-100s of mW output
 - Can be as small as 1K
- Potential system:
 - ΔT air/soil during day, night
 - Calculations show feasibility of concept for very low wind speed values (0.5 to 0.75 m/s)
 - Operating current and voltage can be tailored by using parallel strings of TE legs
 - Power conditioning



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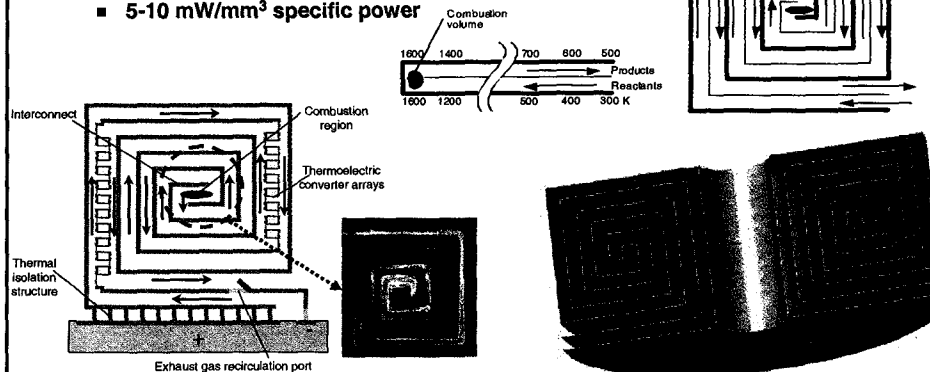


MicroFire Power Source



- USC/MemGen Inc./JPL collaboration

- "Swiss roll" heat recirculating burner with toroidal 3-D geometry
- Thermoelectric elements embedded into structure
- Monolithic fabrication of the entire device using electrochemical fabrication
- 5-10 mW/mm³ specific power



3-D toroidal Swiss roll microcombustor/generator

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Drive for Increased Miniaturization

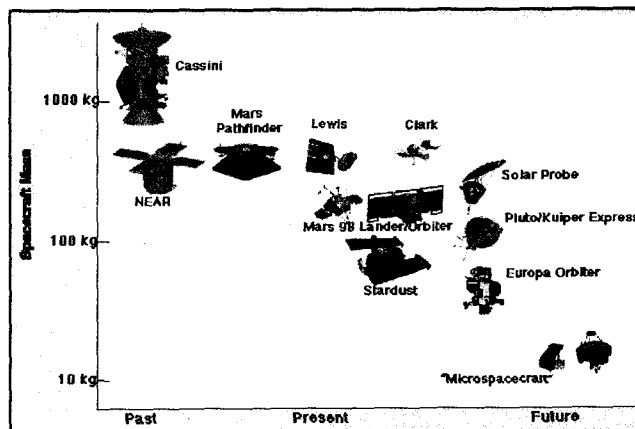


Micro/nano sciencecrafts for deep space exploration

Increased miniaturization



Increased integration of sciencecraft functions and components



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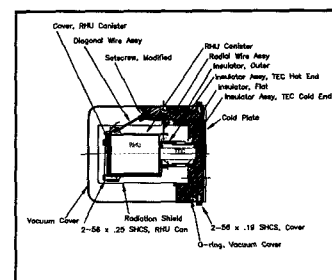
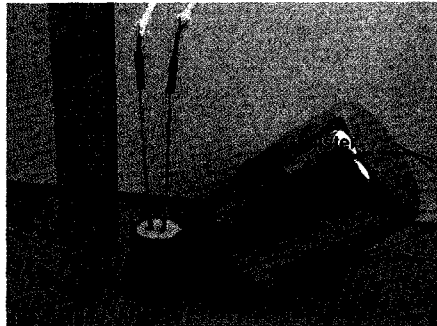
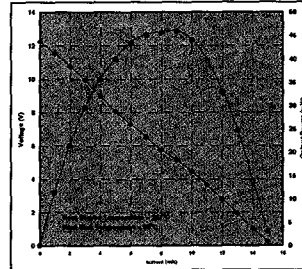
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Milliwatt Power Source (MWPS)



- **MWPS: a miniature radioisotope thermoelectric generator**
 - 1.1 W RHU (Radioisotope Heater Unit, 26 mm Ø x 32 mm long, 40 g weight)
 - 18x18 thermopile array of Bi_2Te_3 thermoelectric elements
 - 7.4 x 7.4 x 23 mm dimensions, $T_{\text{hot}} = 228^\circ\text{C}$, $T_{\text{cold}} = 25^\circ\text{C}$
 - Packaging canister
 - Optimized design being developed by HI-Z technologies
- **5.5 V_{DC}, 45 mW electrical power output, 350 g overall weight**
 - Can be combined with rechargeable batteries, or ultra-capacitors for low duty cycle, higher power output
 - Design could be modified to accommodate two or more RHU
 - Will improve specific power by at least 30%



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Micropower for Outer Planets missions

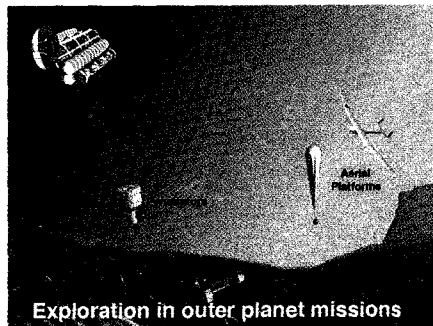


⇒ Outer Planets exploration activities

- Through ice, water, cryogenic liquids, hot gases, high g loads, moderate to high radiation
- Such as for Europa landers, Titan explorers, Comet sample return vehicles...

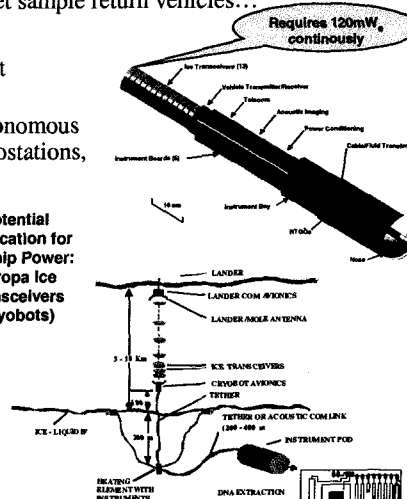
⇒ Need for miniaturized robust power sources

- To enable/prolong planetary exploration, to permit novel/more science measurements
- To enable development of novel miniaturized autonomous probes such as drop-off penetrators, weather microstations, communication relay devices, etc...



Exploration in outer planet missions

Potential Application for On-chip Power: Europa Ice Transceivers (cryobots)



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On-Chip Power Source



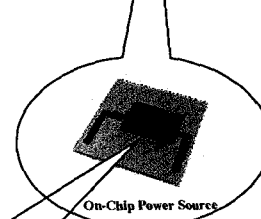
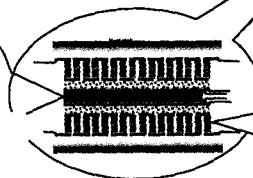
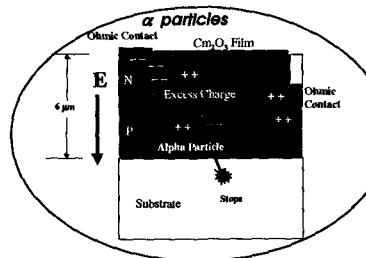
■ Need for highly miniaturized power sources

- NASA missions call for use of a number of small, compact vehicles for exploring a great variety of environments
 - Cold, hot, high g, high radiation, no sun light...
 - Long life characteristics highly desirable (includes shelf life)
- Ultimate goal is to have power integrated within SOAC-type chip architecture
 - Enabling technology for a variety of sensors and other electronic, optoelectronic components
- Do better than electrochemical batteries!

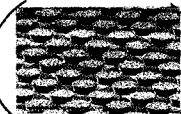


Novel Technology Target Performance vs SOA:

System	SiGe RTG	MWPS	On-Chip μ -RTG
Power	280W	40 mW	1 ~ 100 mW
Sp. Power	5 W/kg	8 μ W/mm ³	~ 1mW/mm ³



Thermoelectrics



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TE Microdevice Development

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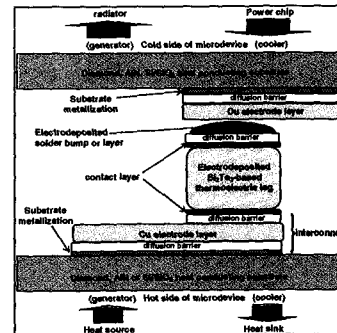
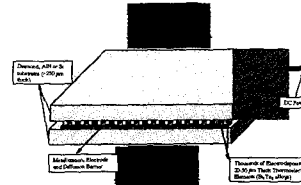


Electrochemical Deposition for Thermoelectric Microdevices



Key challenges for TE microdevice fabrication

- Electrochemistry
 - n-type and p-type $\text{Bi}_{2-x}\text{Sb}_x\text{Te}_3$ deposition
 - Optimization of thermoelectric properties
 - Morphology and stress control of semiconducting and metallic electrodeposits
- Photoresist (PR):
 - High aspect ratio patterns in up to 75 μm thick PR
 - Multiple processing of PR layers
 - Post-fabrication removal of processed thick PR layers
- Legs and interconnects
 - Adhesion between metal and semiconductor layers
 - Removal of metallic layers without damage to semiconductors
 - Alignment between multiple fabrication steps
 - Mechanical strength and resistance to high temperature anneals



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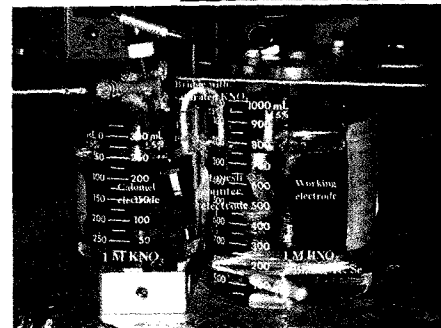
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TE Microdevice Fabrication



- An attractive route to deposition of thick films of TE materials
 - High deposition rate on metallic substrates
 - Room temperature process, inexpensive, and scalable
- $\text{Bi}_{2-x}\text{Sb}_x\text{Te}_{3-y}\text{Se}_y$ deposition
 - $13\text{H}^+ + 18\text{e}^- + 2\text{BiO}^+ + 3\text{HTeO}_2^+ \rightarrow \text{Bi}_2\text{Te}_3\downarrow + 8\text{H}_2\text{O}$
 - JPL using potentiostatic control
 - Manual, computer-controlled equipment
 - Many process parameters
 - Deposition voltage, current
 - [Bi] concentration, [Bi]/[Te] ratio...
 - Deposition setup, stirring rate, substrate quality, pH, temperature
- Deposition of other metallic layers
 - Cu, Ni, Pt, PbSn solder...
- Up to 11,000 legs grown using a 30 μm pitch
 - In 3x3 mm² area



➤ Process offers tremendous *flexibility* for configuring microdevices

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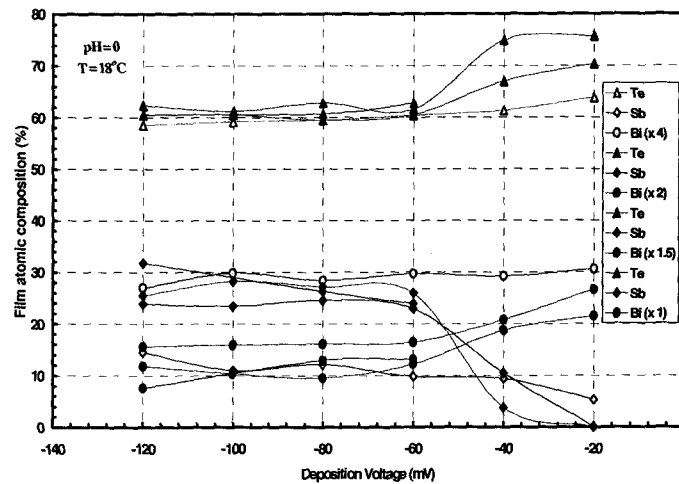
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ECD of Ternary $\text{Bi}_{2-x}\text{Sb}_x\text{Te}_3$



Influence of Sb and Bi concentrations on Ternary $\text{Bi}_{2-x}\text{Sb}_x\text{Te}_3$ Film Composition



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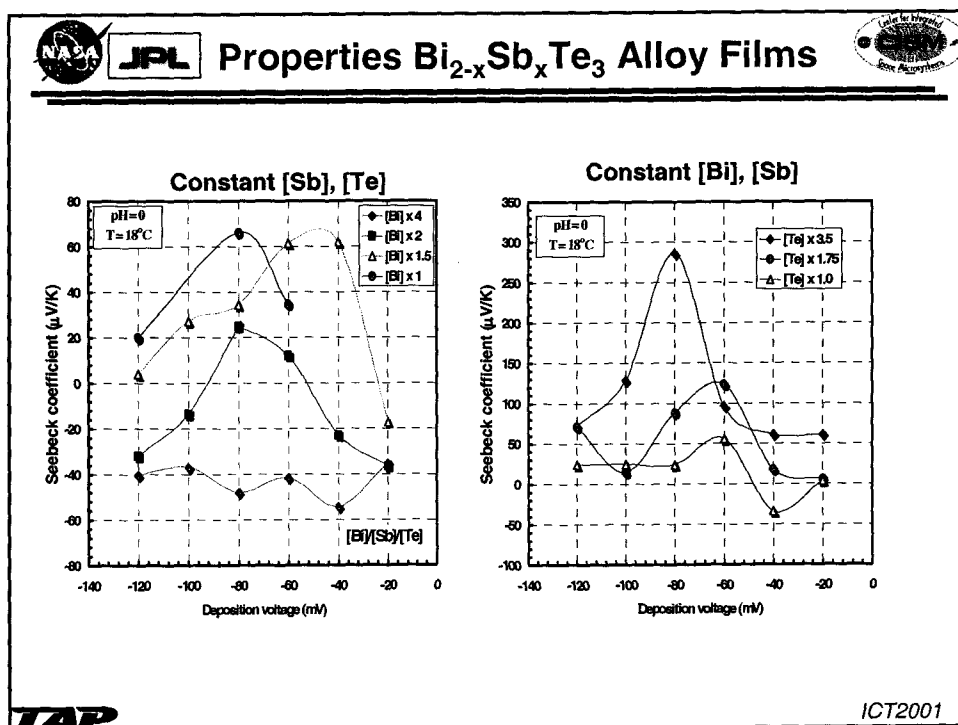
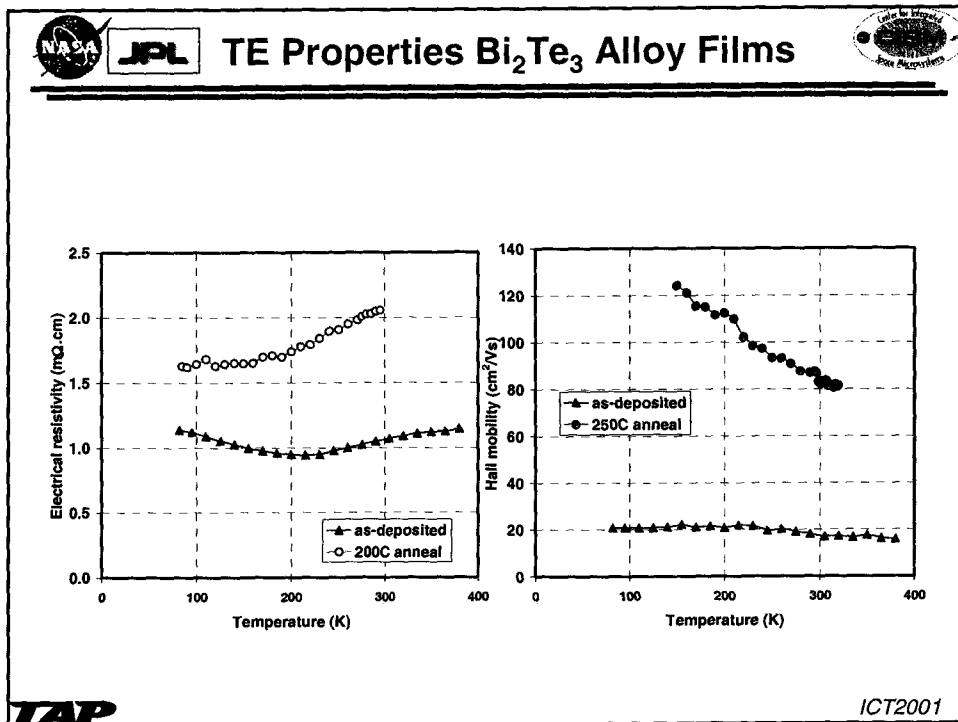
TE Properties Bi_2Te_3 Alloy Films



- As-deposited $\text{Bi}_2\text{Te}_{3-x}\text{Se}_x$ films
 - Show heavily doped n-type behavior
 - $S = -40$ to $-60 \mu\text{V/K}$; (cross-plane measurement)
 - $\rho \sim 1 \text{ m}\Omega\text{cm}$; $n \sim 1 \times 10^{20} \text{ cm}^{-3}$; $\mu_n \sim 15\text{-}25 \text{ cm}^2\text{V}^{-1}\text{s}^{-1}$ (in-plane measurement)
 - $\lambda = 11 \text{ mW/cmK}$; (AC calorimetry in-plane measurement, 3-w measurement underway)
- Electrical properties are improved by anneals
 - Doping levels decrease and carrier mobilities increase
 - S up to $-200 \mu\text{V/K}$ after 250°C anneal
 - $\rho = 2\text{-}3 \text{ m}\Omega\text{cm}$; μ_n up to $80 \text{ cm}^2\text{V}^{-1}\text{s}^{-1}$ (in-plane measurement)
- As-deposited $\text{Bi}_{2-x}\text{Sb}_x\text{Te}$ films
 - As deposited: Seebeck values range from -60 to $+250 \mu\text{V/K}$
 - Seebeck values highly sensitive to film stoichiometry
 - Excess Te, Bi/Sb atomic ratio
 - Heat treatment study
 - Anneals in 200 to 300°C range improve p-type character of films
 - As for n-type, annealing of defects with donor-like behavior
- More work to be done to complete characterization
 - Film-level and device-level measurements

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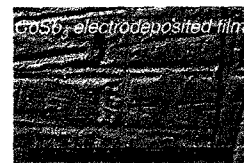
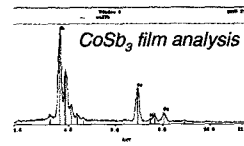
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ECD of other TE Materials



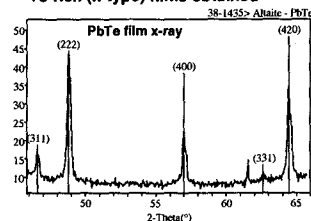
- Exploring practical approaches to the electrodeposition of attractive TE materials for high temperature operation

- PbTe and its alloys
 - ♦ Also PbTe-Bi₂Te₃ based layered compounds
- Skutterudites such as CoSb₃



- Experimental results to date on PbTe

- Also using acidic PbTe aqueous solution
 - ♦ Pb+Te codeposition in -130 to -400 mV vs. SCE range
 - ♦ Both Pb-rich (p-type) and Te-rich (n-type) films obtained



- Experimental results to date on CoSb₃

- Near neutral Co/Sb aqueous electrolyte at room temperature
 - ♦ Chelating agents
- Codeposition of Co and Sb
 - ♦ From same bath
 - ♦ Some deposition conditions lead to mostly CoSb₃ phase
 - ♦ Characterization under way

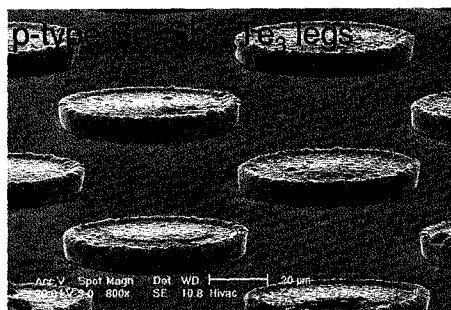
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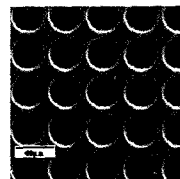


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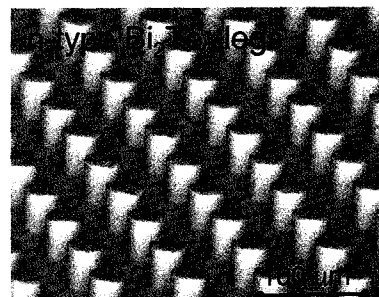
Electrochemically Deposited Bi₂Te₃ Legs Using Thick Photoresist Templates



Photoresist template (top)



Photoresist template (side)

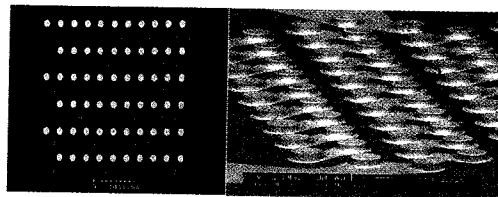
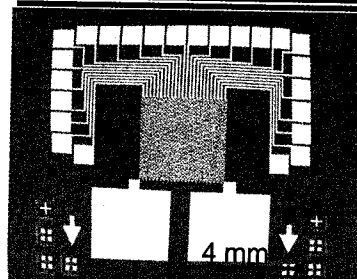


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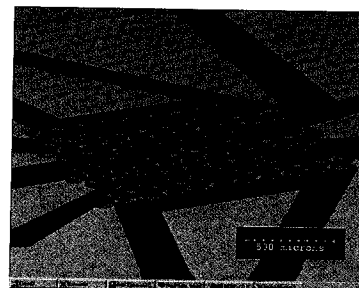
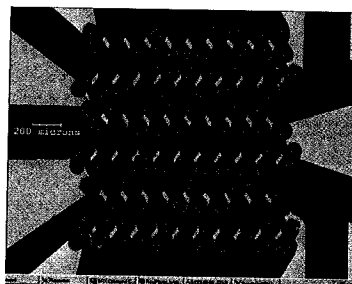
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TE Microdevice Fabrication



TEMD Patterned metallizations, interconnects and legs



Full 3-D TEMD structure fabrication

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TE Microdevices: First demonstration

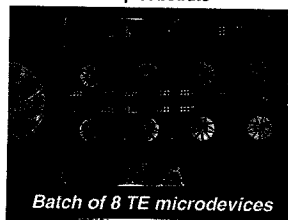


TE microdevice fabrication status

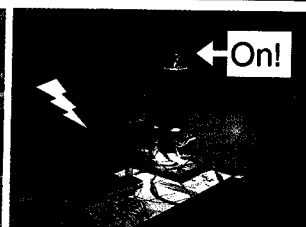
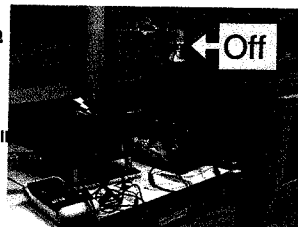
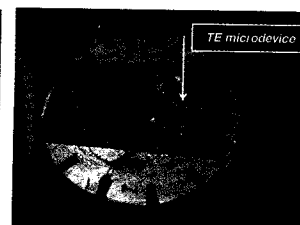
- Many 3-D TE microdevice structures have been fabricated
 - Most of them have one set of n-type Bi_2Te_3 legs and one set of metallic legs
- First 3-D structures with sets of n-type and p-type legs now being fabricated
 - Also working on full device that include a top substrate

First TEMD demos

- n- Bi_2Te_3 /Au devices
- Devices heat-treated at elevated temperatures
- Heated on top by lamp
- Small amount of power generated
 - From each string of 22 legs
- String resistance as low as 2Ω
 - Means that contact resistivity between interconnects and Bi_2Te_3 is $\sim 10^{-7} \Omega\cdot\text{cm}^2$ or lower
 - More precise measurements will be made soon



Batch of 8 TE microdevices

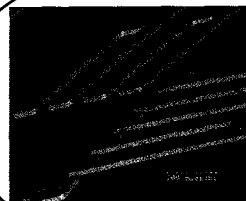
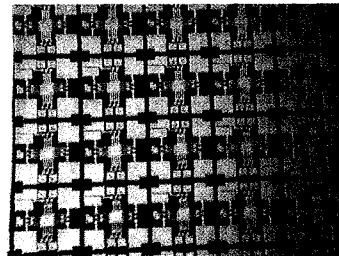
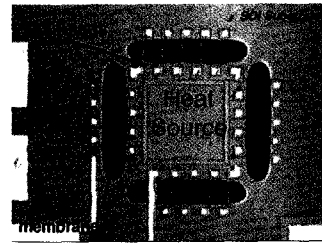
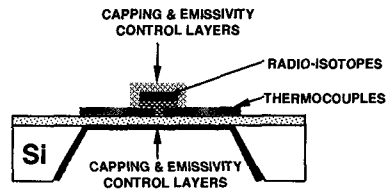


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" μ -ARPS" In Plane TEMG Configurations



In-Plane TE microgenerator ECD/MEMS Fabrication on SOI

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TE Nanodevice Development

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Nanowire Thermoelectric Generator



■ Proof-of-principle microdevice for a high performance microscale nanowire-based thermoelectric generator

- Nanowires as TE legs with 20 nm diameter and 50 to 60 μm height
 - Using anodized alumina templates
 - Using conventional microelectronics processing techniques
 - Quantum confinement, interface scattering could lead to 4-5% efficiency at $\Delta T = 50\text{K}$
 - High power density from thousands of legs
 - $>> 1000,000$ in 1 cm^2
 - Open Circuit Voltage $> 100\text{ V}$ for $\Delta T = 50\text{K}$

• For energy harvesting application

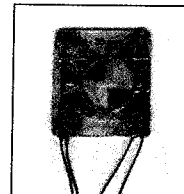
- Energy harvesting of rejected heat in various structures to increase overall efficiency, autonomy
 - Rejected heat on solar arrays, small spacecraft
- Power for microdevices
 - High voltage even with small ΔT
 - Power for science instruments, sensors, SOAC
- Other waste heat recovery applications

■ Experimental results to date

- Grew n-type Bi_2Te_3 and p-type $\text{Bi}_{2-x}\text{Sb}_x\text{Te}_3$ nanowires electrochemically
 - Up to 60 μm long
- Developed methods for processing nanowires
 - Electrodeposited 10-20 nm x 40 μm Bi_2Te_3 elements
- Conducting studies to make 10 nm alumina templates
- Measured some thermoelectric characteristics of n-type Bi_2Te_3 wires
 - Seebeck Coefficient as high as $-125\text{ }\mu\text{V/K}$
- Initiated collaborations with various universities



Nanowire-based, small ΔT , high voltage microgenerator (concept)



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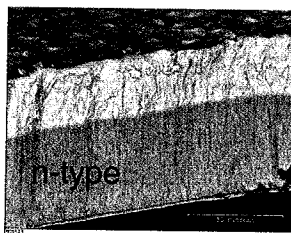
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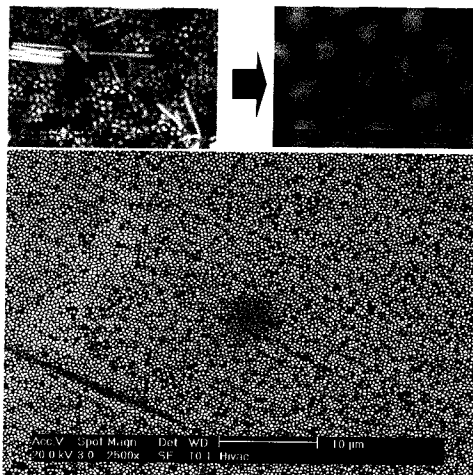
Electrodeposition into Nanostructured Templates



■ Both n-type and p-type $\text{Bi}_{2-x}\text{Sb}_x\text{Te}_3$ nanowires



■ Polished top surface of Bi_2Te_3 nanowires filling an anodized alumina template



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TEMDs: Summary



- **Many applications available if thermoelectric microdevices can successfully demonstrate predicted performance**
- **Waste heat recovery and spot cooling are promising areas**
 - Microgenerators and microcoolers for integration with electronics
 - ♦ New technology based on electrochemistry of SOA materials
 - ♦ Batch fabrication possible
 - ♦ Technology and lessons learned could later be used for application of low dimensional structures in TE devices
- **SOAC-like technical approach for use of TE micro/nanodevices**
 - Distributed architecture for power thermal management where it is needed
 - ♦ Enhanced autonomy, reliability
 - ♦ Modular, scalable technology: ECD, CVD, IC, MEMS
 - **Embedded, rugged power sources:**
 - ♦ Waste heat, energy harvesting, combustion, radioisotope heat sources
 - ♦ High specific power could be possible: mW/mm² capability
 - ♦ Hybrid conversion and conversion/storage solid-state systems
 - Integrated cooling/thermal management
 - ♦ Cooling device fabrication and integration technology compatible with electronics/optoelectronics
 - ♦ Hybrid cooling technologies